

N-Channel 30-V (D-S) MOSFET

PRODUCT SUMMARY					
V _{DS} (V)	$R_{DS(on)}\left(\Omega\right)$	I _D (A) ^a	Q _g (Typ.)		
30	0.012 at V _{GS} = 10 V	16	10 nC		
	0.016 at V _{GS} = 4.5 V	14	10110		

SO-8 S 1 8 D S 2 7 D S 3 6 D Top View

Ordering Information: Si4890BDY-T1-E3 (Lead (Pb)-free)

Si4890BDY-T1-GE3 (Lead (Pb)-free and Halogen-free)

FEATURES

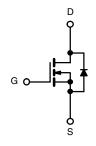
- Halogen-free According to IEC 61249-2-21 Available
- TrenchFET[®] Power MOSFET
- 100 % R_g and UIS Tested

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ROHS COMPLIANT HALOGEN FREE

APPLICATIONS

- Notebook
 - System Power
 - Adapter Switch
- DC/DC



N-Channel MOSFET

Parameter		Symbol	Limit	Unit	
Drain-Source Voltage		V_{DS}	30	V	
Gate-Source Voltage		V_{GS}	± 25	v	
	T _C = 25 °C		16		
Continuous Drain Current (T _{.1} = 150 °C)	T _C = 70 °C	1	12.9		
Continuous Diain Current (1) = 150 °C)	T _A = 25 °C	- I _D	10.7 ^{b, c}		
	T _A = 70 °C		8.6 ^{b, c}	Α .	
Pulsed Drain Current		I _{DM}	60		
Continuous Source-Drain Diode Current	T _C = 25 °C		5.1		
Continuous Source-Drain Diode Current	T _A = 25 °C	Is	2.2 ^{b, c}		
Single Pulse Avalanche Current	L = 0.1 mH	I _{AS}	20		
Avalanche Energy	L=0.11IIII	E _{AS}	20	mJ	
	T _C = 25 °C		5.7		
Maximum Power Dissipation	T _C = 70 °C	D_	3.6	w	
	T _A = 25 °C	P _D	2.5 ^{b, c}	VV	
	T _A = 70 °C		1.6 ^{b, c}		
Operating Junction and Storage Temperature	e Range	T _J , T _{stg}	- 55 to 150	°C	

THERMAL RESISTANCE RATINGS						
Parameter		Symbol	Typical	Maximum	Unit	
Maximum Junction-to-Ambient ^{b, d}	t ≤ 10 s	R_{thJA}	40	50	°C/W	
Maximum Junction-to-Foot (Drain)	Steady State	R_{thJF}	18	22		

Notes:

- a. Based on $T_C = 25$ °C.
- b. Surface Mounted on 1" x 1" FR4 board.
- c. t = 10 s.
- d. Maximum under Steady State conditions is 90 °C/W.

Si4890BDY

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Parameter	Symbol	Test Conditions	Min.	Тур.	Max.	Unit	
Static				7.		l	
Drain-Source Breakdown Voltage	V _{DS}	$V_{GS} = 0 \text{ V}, I_D = 250 \mu\text{A}$	30			V	
V _{DS} Temperature Coefficient	$\Delta V_{DS}/T_{J}$	J 050 A		36		mV/°C	
V _{GS(th)} Temperature Coefficient	$\Delta V_{GS(th)}/T_{J}$	I _D = 250 μA		- 6.2			
Gate-Source Threshold Voltage	V _{GS(th)}	$V_{DS} = V_{GS}$, $I_{D} = 250 \mu\text{A}$	1.4		2.6	V	
Gate-Source Leakage	I _{GSS}	$V_{DS} = 0 \text{ V}, V_{GS} = \pm 25 \text{ V}$			± 100	nA	
Zero Gate Voltage Drain Current	I _{DSS}	V _{DS} = 30 V, V _{GS} = 0 V			1	μΑ	
		$V_{DS} = 30 \text{ V}, V_{GS} = 0 \text{ V}, T_{J} = 55 ^{\circ}\text{C}$			10		
On-State Drain Current ^a	I _{D(on)}	$V_{DS} \ge 5 \text{ V}, V_{GS} = 10 \text{ V}$	30			Α	
	R _{DS(on)}	V _{GS} = 10 V, I _D = 10 A		0.009	0.012	Ω	
Drain-Source On-State Resistance ^a		$V_{GS} = 4.5 \text{ V}, I_D = 8 \text{ A}$		0.012	0.016		
Forward Transconductance ^a	g _{fs}	V _{DS} = 15 V, I _D = 10 A		30		S	
Dynamic ^b			L			ı	
Input Capacitance	C _{iss}			1535			
Output Capacitance	C _{oss}	$V_{DS} = 15 \text{ V}, V_{GS} = 0 \text{ V}, f = 1 \text{ MHz}$		255		pF	
Reverse Transfer Capacitance	C _{rss}			106			
Tatal Cata Chausa		V _{DS} = 15 V, V _{GS} = 10 V, I _D = 10 A		22	33	nC	
Total Gate Charge	Q _g			10	15		
Gate-Source Charge	Q_{gs}	$V_{DS} = 15 \text{ V}, V_{GS} = 4.5 \text{ V}, I_{D} = 10 \text{ A}$		4.3			
Gate-Drain Charge	Q_{gd}			2.6			
Gate Resistance	R_g	f = 1 MHz		0.77	1.5	Ω	
Turn-On Delay Time	t _{d(on)}			20	40	ns	
Rise Time	t _r	V_{DD} = 15 V, R_L = 1.5 Ω		10	20		
Turn-Off Delay Time	t _{d(off)}	$I_D \cong 5 \text{ A}, V_{GEN} = 4.5 \text{ V}, R_g = 1 \Omega$		20	40		
Fall Time	t _f			8	16		
Turn-On Delay Time	t _{d(on)}			11	22		
Rise Time	t _r	V_{DD} = 15 V, R_L = 1.5 Ω		8	16		
Turn-Off Delay Time	t _{d(off)}	$I_D\cong$ 5 A, V_{GEN} = 10 V, R_g = 1 Ω		20	40		
Fall Time	t _f			8	16		
Drain-Source Body Diode Characterist	ics						
Continuous Source-Drain Diode Current	I _S	T _C = 25 °C			5.1	A	
Pulse Diode Forward Current ^a	I _{SM}		60		60		
Body Diode Voltage	V_{SD}	I _S = 3 A		0.76	1.1	V	
Body Diode Reverse Recovery Time	t _{rr}			24	40	ns	
Body Diode Reverse Recovery Charge	Q _{rr}	I _F = 5 A, dl/dt = 100 A/μs, T _{.l} = 25 °C		18	30	nC	
Reverse Recovery Fall Time	t _a	$I_F = 5 \text{ A}, \text{ ul/ul} = 100 \text{ A/}\mu\text{s}, I_J = 25 \text{ °C}$		14		200	
Reverse Recovery Rise Time	t _b	1		10		ns	

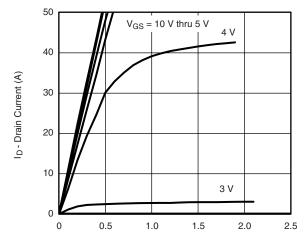
- a. Pulse test; pulse width \leq 300 μ s, duty cycle \leq 2 %
- b. Guaranteed by design, not subject to production testing.

Stresses beyond those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated in the operational sections of the specifications is not implied. Exposure to absolute maximum rating conditions for extended periods may affect device reliability.



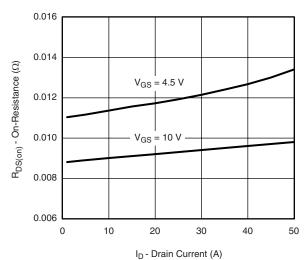
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TYPICAL CHARACTERISTICS 25 °C, unless otherwise noted

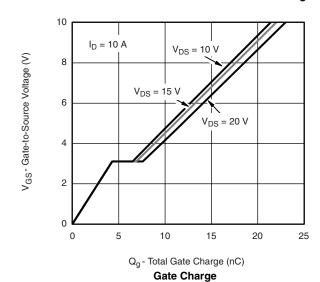


V_{DS} - Drain-to-Source Voltage (V)

Output Characteristics



On-Resistance vs. Drain Current and Gate Voltage

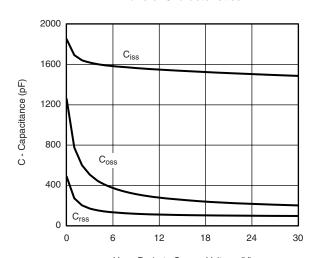


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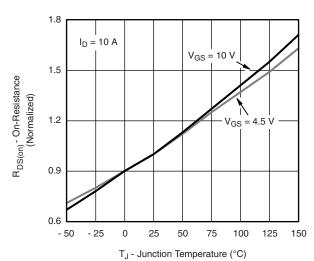
V_{GS}- Gate-to-Source Voltage (V)

Transfer Characteristics



V_{DS} - Drain-to-Source Voltage (V)

Capacitance



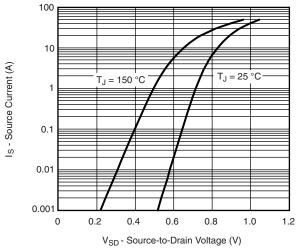
On-Resistance vs. Junction Temperature

Si4890BDY

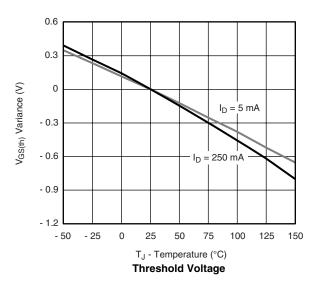
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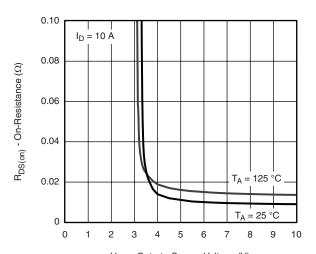
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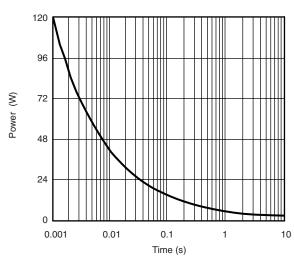
TYPICAL CHARACTERISTICS 25 °C, unless otherwise noted



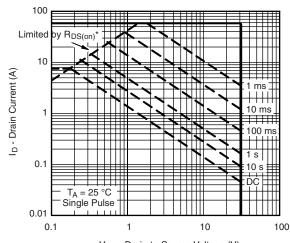
Source-Drain Diode Forward Voltage







Single Pulse Power, Junction-to-Ambient



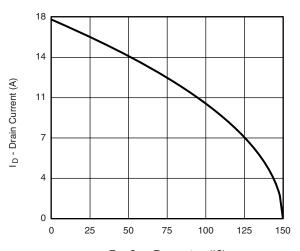
 $$V_{DS}$$ - Drain-to-Source Voltage (V) $$^*V_{GS}$$ > minimum V_{GS} at which $R_{DS(on)}$ is specified

Safe Operating Area, Junction-to-Ambient



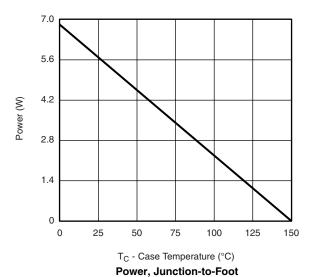
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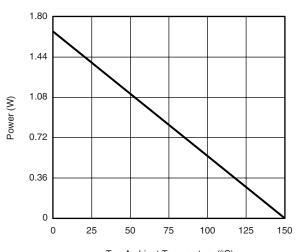
TYPICAL CHARACTERISTICS 25 °C, unless otherwise noted



 $T_{\mbox{\scriptsize C}}$ - Case Temperature (°C)

Current Derating*





T_A - Ambient Temperature (°C)

Power, Junction-to-Ambient

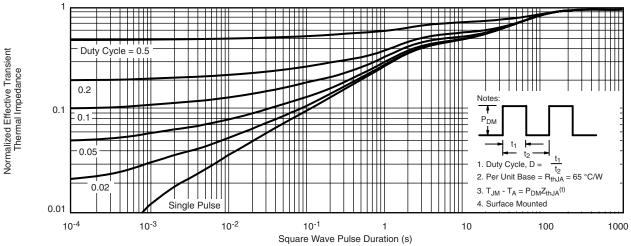
^{*} The power dissipation P_D is based on $T_{J(max)} = 150$ °C, using junction-to-case thermal resistance, and is more useful in settling the upper dissipation limit for cases where additional heatsinking is used. It is used to determine the current rating, when this rating falls below the package limit.

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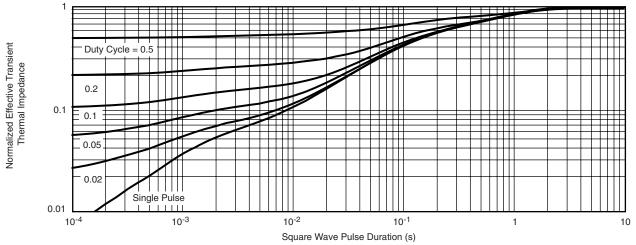
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TYPICAL CHARACTERISTICS 25 °C, unless otherwise noted



Normalized Thermal Transient Impedance, Junction-to-Ambient



Normalized Thermal Transient Impedance, Junction-to-Case

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Document Number: 91000 Revision: 18-Jul-08